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**SOCRADES**

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**Service-Oriented Cross-layer infRAstructure for  
Distributed smart Embedded devices**

Proposal/Contract No: EU FP6 IST-5-034116 IP SOCRADES

## **Deliverable D5.6.4**

### **Cost Analysis of Proposed $\mu$ Gateway**

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<sup>2</sup> See Annex A for explanation of Dissemination Levels, as defined in the DoW

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0.2	17.04.2009	Added detailed silicon estimations from model. Typo fixing and minor rephrasing	ARM/JJ
0.1	06.04.2009	Draft revision	ARM/JJ

<sup>3</sup> As defined in the DoW

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<sup>5</sup> A list of company short tags can be found in DoW

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### Dissemination Level:

PU	Public
PP	Restricted to other programme participants (including the Commission Services)
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## 1. Introduction

The evaluation prototype hardware has been realized in an FPGA-based solution on a customized evaluation board hardware. This is very useful during debugging and implementation phase due to low cost & effort for required hardware changes in functionality. Additionally several I/O interfaces can be implemented according to requirements of the application space in industrial networking and an e.g. independent BLDC-motor controller.

For volume production an ASIC-based silicon solution is the far better solution due to usually higher performance figures and reduced cost for production volume due to specialized silicon of certain functionality on a smaller silicon-die size.

This report shall give an overview for a silicon cost-estimation based on selected functionality for an industrial uGateway controller and detailed information on main cost-driving factors and proposal for dedicated cost savings. For this deliverable document some estimation has been made based on today silicon technology and its availability.

## 2. Architectural and Design

### 2.1. Motivation

The evaluation prototype hardware shall be transferred from a FPGA based solution into an ASIC for high volume production to lower cost for implementations in the industrial networking field. Especially small sensors and actuators are under price pressure due to frequency of occurrence in industrial installations for a certain industrial functionality and facility.

### 2.2. New Capabilities for Industrial Computing

The MCU core called ‘Merlin’ will be the first solution for small embedded industrial networking solutions which introduces several new computing functionality derived from high performance computing solutions into low cost MCUs. Those functionalities are:

- Single Instruction Multiple Data (SIMD) to improve MCU networking stack processing
- DSP functionality to improve complex software algorithms
- Floating point support for Modeling Tool interaction

All new functionality is intended to improve operation of software (e.g. DPWS) on industrial hardware implementations as well as reducing cost by integrating external functionality on one single die and silicon chip for the very first time.

### 2.3. MCU Core Functional Overview

MCU core of a processor for the evaluation prototype hardware exists with the following top level structure. Further I/O interfaces required for the evaluation prototype hardware realisation will be included in chapter 3.2 (but seem to be less important cost factors).

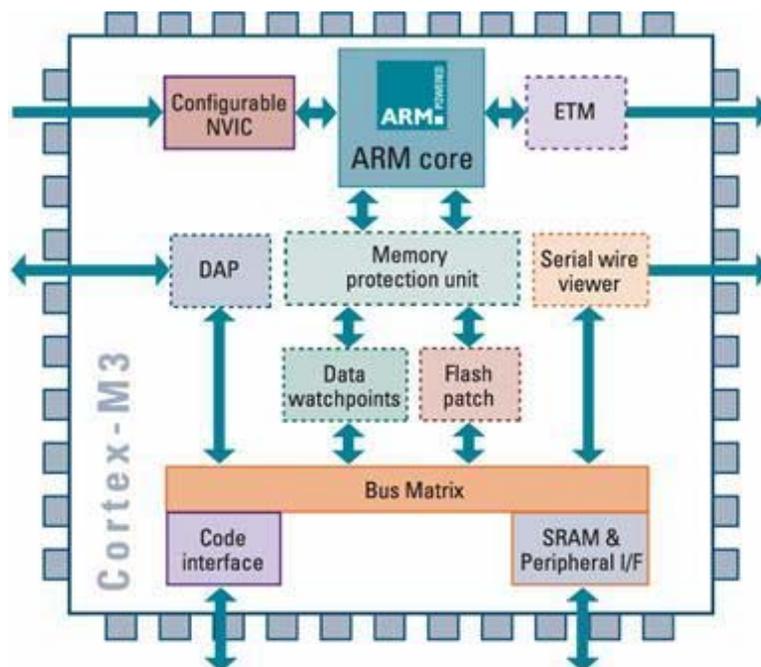


Figure 1: Abstract top level block diagram of Cortex-M3 MCU

## 2.4. Main MCU Core Components

The main components of the Cortex-M3 MCU, as identified in Figure 1 are outlined below.

<b>ARM core -</b>	The central processing unit, or processor core, controls the flow of instruction execution and data processing.
<b>Bus Matrix -</b>	Instruction and data memory is external to the MCU. The bus matrix arbitrates the flow of data from memory and peripheral components, as determined by the CPU.
<b>Memory Protection Unit -</b>	The MPU ensures that accesses to the defined regions of external memories and peripherals are valid.
<b>Flash Patch -</b>	The Flash Patch component provides the ability to replace erroneous code in the fixed instruction ROM with corrected code in changeable memory such as RAM or Flash ROM.
<b>DAP -</b>	The Debug Access Port provides and controls access to the MCU memories and registers for debugging purposes. An external debugging tool communicates with the DAP via a serial debug interface.
<b>ETM -</b>	The Embedded Trace Macro cell provides a stream of information at real-time, that allows the instruction execution flow of the MCU to be monitored externally.
<b>Data Watch points -</b>	This component, under debug control, monitors data transfers for specified data items. Upon detection of such data during program execution, this block triggers or halts trace execution by the ETM.
<b>Serial Wire Viewer -</b>	This component formats trace information from the ETM as standard ASCII data, sent serially to trace analysis tools through a single pin.
<b>NVIC -</b>	The Nested Vectored Interrupt Controller provides a configurable number of interrupts to the MCU, with selectable priority levels. This allows high speed transfer from normal code execution to an Interrupt Service Routine (ISR), and from one ISR to another of higher priority.
<b>Code bus -</b>	2x AHB-Lite buses for instruction code bus and data8Coefficient code bus
<b>SRAM &amp; Peripheral IF</b>	Peripheral bus interfaces for internal SRAM and slow I/O interfaces

## **2.5. I/O Interfaces**

For the evaluation prototype hardware a typical Industrial I/O interface variety has been selected like Ethernet, BLDC-Motor controller, Pulse-width-modulation (PWM), SPI, general purpose IO (GPIO) and common glue logic like reset and clock distribution as well as internal standard bus systems for interconnection purposes.

### 3. Silicon Size Calculation

#### 3.1. Silicon Area Consumption

The calculation is split into two major groups, the gate count and the known length and width of an e.g. memory area in a certain silicon technology. **Note:** This is only an example implementation for illustration considering major required I/O interfaces combined with a huge storage capacity.

#### 3.2. The Silicon Die Size Estimation

The table below shows a typical estimation for an evaluation prototype hardware including ECU core and main peripheral components.

Module	Gate count	Length (um)	Width (um)	Area (mm2)
Cortex-M3 (CM3)	60.000			0
JTAG Interface (Part of CM3)				0
16-input Interrupt Controller (Part of CM3)				0
1M SRAM		8000	5780	46,24
2M Flash Memory		7440	4460	33,18
Memory Interface Unit (PL241)	32.000			0
2x 16-bit timer	4.200			0
32-bit watchdog timer	1.465			0
GPIO (PL061)	1.800			0
SPI (PL022)	7.500			0
AHB (Bridge)	400			0
APB (Bridge)	3.600			0
Power-on-reset		387	387	0,14
Power Controller		500	500	0,25
Clock Synthesizer 60-300MHz PLL	3.000			0
PWM	2.300			0
8-channel 10-bit ADC		435	435	0,18
SCI				0
802.15.4 (Zigbee)				0
CAN2.0C (found 2.0B)	6.500			0
4-channel analogue Output				0
Ethernet 10/100	7.000			0
<b>Totals</b>	<b>129.765</b>			<b>80,01</b>

#### Calculate die Size required for prototype

Assuming a cell density of	120	Kgates/mm2
The total Gate Count of	129.765	Gates
Will occupy an Area of	1,08	mm2
Added to the calculated area of	80,01	mm2
Gives a total logic area of	81,09	mm2

Assuming a utilisation of	70	%
Required die size will be	115,84	mm2

**Table 1: Silicon Die Size Estimation**

### 3.3. The Major Die Size Consumption

As seen from the estimated table above the major silicon area consumption is caused by SRAM or FLASH memory.. The 1 MByte SRAM area is bigger than the 2MByte FLASH memory due to its internal structure. Below there will be a short explanation how this is physically caused by technological implementations.

#### 3.3.1. SRAM Memory

Usually a standard SRAM memory it is built of 6 field-effect transistors. The graphic below may illustrate the principle of a single SRAM cell which stores a single bit-information.

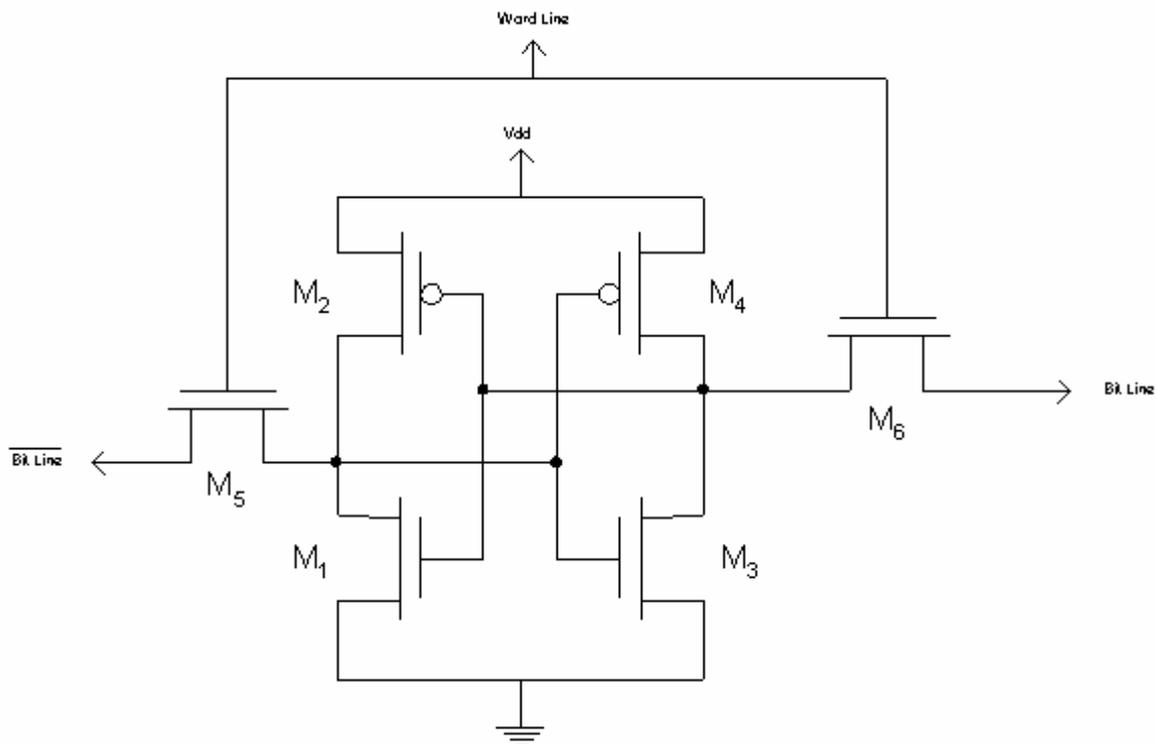


Figure 2: 6T- SRAM Cell (source: [www.cedcc.psu.edu](http://www.cedcc.psu.edu))

SRAM memory cell dimensions are directly dependent on the technology of the silicon manufacturer which will be used for the evaluation prototype hardware ASIC implementation.

#### 3.3.2. FLASH Memory

The structure of a FLASH memory cell is not as easy to describe, because there are two major implementations on the market the fast NOR-FLASH memory technology and a smaller but slower and more reliable NAND-FLASH memory. Additionally there are single level cells (SLC) and multi level cells (MLC) technologies on the market which store one or more physical bits per cell or unit. But as an overall assumption it can be said that a FLASH memory bit cell is built of one special field effect transistor which consumes less silicon die size than a SRAM memory cell. But it is implementation specific which silicon technology is used by silicon manufacturer for the evaluation prototype hardware ASIC implementation of FLASH memory storage.

### 3.4. The Assumption ...

As seen from chapters 3.2 and 3.3 above the major silicon die area consumption is caused by SRAM or FLASH memory. Therefore the functional elements like peripheral I/O or CPU core etc. can be disregarded in further cost and die size estimations. The dominating memory size requirements will be the cost driver, regardless if SRAM-memory or FLASH-memory technology is used.

### 3.5. The Silicon Companies Business ...

Today's silicon manufacturers have to operate on good profit levels to burden cost for running large manufacturing plants and factories. So the production cost of a evaluation prototype hardware can only be estimated to be around half of the selling price to silicon manufacturers customers e.g. distributors. But this estimation is very weak not considering business relationships and purchased volume over time as well as silicon technology used for the evaluation prototype hardware ASIC.

## 4. Cost Estimation & Possible Savings

### 4.1. Estimation of Die Cost

A cost estimation models from common processes from an famous Automotive silicon manufacturer shows cost of around 3-5 US-Dollar per silicon die assuming a 90nm process on 300mm wafers for 1MByte SRAM and 2MByte FLASH memory. Additionally a cost adder of about ~0,50 US-Dollar for additional efforts like packaging, number of pins and testing effort shall be considered. All estimations are based on a year 2008 model, see [12]. The production cost will decrease in a double digit percentage for year 2009 and stabilizes over the year in the future on that level [12].

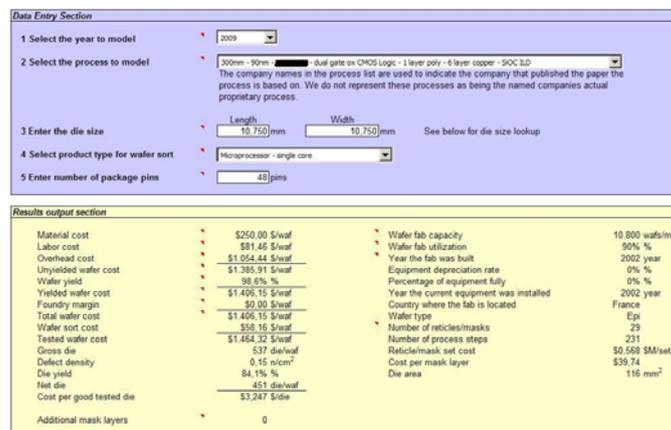


Figure 3: Cost Estimation Example (Max. Memory)

Please note that this is rough cost estimation for the evaluation prototype hardware not considering side effects like special supplier relations, application requirements (e.g. special packaging requirements for high temperature environments), volume production numbers and political stability.

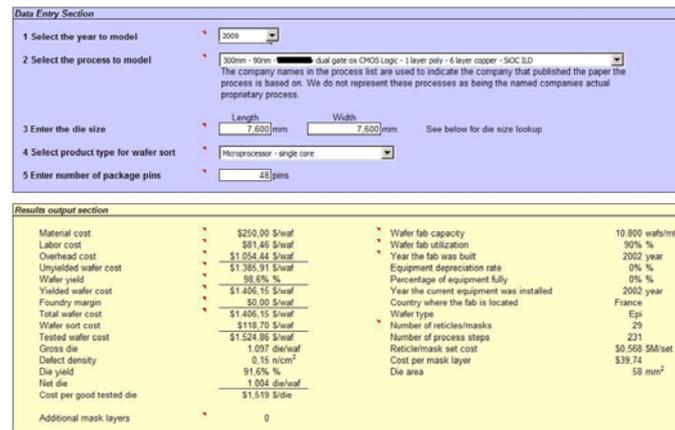
### 4.2. Cost Saving Opportunities

#### 4.2.1. Memory Storage Variants

Due to the fact that SRAM-memory and FLASH-memory consume the majority of the silicon die size, a reduction of memory requirements will dramatically reduce production cost per die.

For example a 50% reduction of the die size from around 116mm<sup>2</sup> to 58mm<sup>2</sup> will reduce the silicon die size cost of about 55% in 2008 with an outlook to shrink down to ~25% in 2015. General conditions for the numbers as mentioned before are extremely dependent on technology framework [12].

As a consequence, storage space in SRAM-memory and FLASH-memory used by software implementation solution has a direct impact on evaluation prototype hardware ASIC cost. It is recommended that highly size-optimized software shall be used to run an application; it has direct impact in the cost and cost-savings.



The screenshot shows a software interface for cost analysis, divided into two main sections: 'Data Entry Section' and 'Results output section'.

**Data Entry Section:**

- 1 Select the year to model: 2009
- 2 Select the process to model: 30nm - 90nm - dual gate ex CMOS Logic - 1 layer poly - 6 layer copper - SOC.BD
- 3 Enter the die size: Length 7,600mm, Width 7,600mm
- 4 Select product type for wafer sort: Microprocessor - single core
- 5 Enter number of package pins: 48 pins

**Results output section:**

Material cost	\$250.00 \$/waf	Wafer fab capacity	10,800 wafers/mth
Labor cost	\$81.46 \$/waf	Wafer fab utilization	90% %
Overhead cost	\$1,954.44 \$/waf	Year the fab was built	2002 year
Unyielded wafer cost	\$1,385.91 \$/waf	Equipment depreciation rate	0% %
Wafer yield	98.6% %	Percentage of equipment fully	0% %
Yielded wafer cost	\$1,406.15 \$/waf	Year the current equipment was installed	2002 year
Foundry margin	\$0.00 \$/waf	Country where the fab is located	France
Total wafer cost	\$1,406.15 \$/waf	Wafer type	Epi
Wafer sort cost	\$110.70 \$/waf	Number of reticles/masks	29
Tested wafer cost	\$1,520.96 \$/waf	Number of process steps	231
Gross die	1.097 die/waf	Reticle/mask set cost	\$0,568 \$M/set
Defect density	0.15 n/cm <sup>2</sup>	Cost per mask layer	\$39.74
Die yield	91.6% %	Die area	58 mm <sup>2</sup>
Net die	1.004 die/waf		
Cost per good tested die	\$1,519 \$/die		
Additional mask layers	0		

Figure 4: Cost Savings Example (Smaller Memory)

#### 4.2.2. Core Substitution Efficiency

Besides the memory variants, the gate count for the evaluation prototype hardware can be further reduced by replacing the Cortex-M3 MCU with a Cortex-M0 MCU. The Cortex-M0 provides a slightly lower performance for sensor/actuator application processing but a drastically reduced gate count of about ~12K gates (=80%) on a lower power consumption level but it maintains full software code compatibility at the same time.

Additionally this may be beneficial in cases of Automotive requirements or Analog and even Mixed-Signal solutions for e.g. integrated physical sensors which may require larger gate geometries due to the use-case and therefore larger die sizes in some implementation cases which drives into higher cost issues.

#### 4.2.3. Instruction Set Capabilities

As mentioned in [12] the application software implementation of the evaluation prototype hardware can be improved by using a hardware SIMD-instruction set implementation which helps to speedup code execution on one hand and reduces size of the application code executable on the other hand.

Especially in the case where the hardware geometry can physically shrink to smaller geometries in advanced silicon technologies without affecting the functionality of the ASIC (e.g. no pad limitations), instruction set support for efficient software generation might be helpful to consume even less memory as well. SIMD instructions provide much more flexibility to the code compiler to optimize and profile e.g. certain software algorithms by replacing large software library functions with instructions built in hardware (e.g. instructions for matrix multiplication etc.).

## 5. References

### 5.1. Input Documents

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Cortex-M3 Engineering Specification (confidential), 2008, ARM Limited, Cambridge, UK
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Information on principle SRAM memory implementation and related functionality, 2009,  
<http://www.cedcc.psu.edu/khanjan/vssram.htm>
- [11]  
IC Knowledge LLC, IC Cost Model, 2008, revision 0808,
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**5.2. Related standards and norms**

- None -

## 6. Acronyms and Abbreviations

<i>Abbreviation / Acronym:</i>	<i>Description:</i>
ECU/MCU	Microcontroller (Unit)
SIMD	Single Instruction Multiple Data
RISC	Reduced Instruction Set Computer
ETM	Embedded Trace Macro cell
NVIC	Nested Vector Interrupt Controller
WIC	Wake-up Interrupt Controller
DAP	Debug Access Port
DSP	Digital Signal Processor / Processing
IP	Intellectual Property
CPU	Central Processing Unit
I/O	Input/Output Interface
die	Piece of silicon which realizes the required MCU functionality without package

**Table 2: Acronyms & Abbreviations**

As this is a document from professionals for professionals, all other terms are expected to be known.

## 7. Annex A – Dissemination Levels

PU	Public
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**Table 3: Dissemination levels for a document**